What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	XC800
Core Size	8-Bit
Speed	24MHz
Connectivity	CANbus, SSI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	48
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.75K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	PG-TQFP-64
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/sak-xc888cm-8ffa-ab

XC886/888 Data Sheet

Revision History: V1.2 2009-07

Previous Versions: V1.0, V1.1	
Page	Subjects (major changes since last revision)
Changes from V1.1 2009-01 to V1.2 2009-07	
89	Note on LIN baud rate detection is added.
92	RXD slave line in SSC block diagram is updated.
108	Electrical parameters are now valid for all variants, previous note on exclusion of ROM variants is removed.
116	Symbol for ADC error parameters are updated.
120	Power supply current parameters for ROM variants are updated.
128	Test condition for the on-chip oscillator short term deviation is updated.

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code or data. Therefore, even though the ROM device contains either a 24-Kbyte or 32-Kbyte ROM, the maximum size of code that can be placed in the ROM is the given size less four bytes.

3.2.1 Memory Protection Strategy

The XC886/888 memory protection strategy includes:

- Read-out protection: The user is able to protect the contents in the Flash (for Flash devices) and ROM (for ROM devices) memory from being read
  - Flash protection is enabled by programming a valid password (8-bit non-zero value) via BSL mode 6.
  - ROM protection is fixed with the ROM mask and is always enabled.
- Flash program and erase protection: This feature is available only for Flash devices.

3.2.1.1 Flash Memory Protection

As long as a valid password is available, all external access to the device, including the Flash, will be blocked.

For additional security, the Flash hardware protection can be enabled to implement a second layer of read-out protection, as well as to enable program and erase protection.

Flash hardware protection is available only for Flash devices and comes in two modes:

- Mode 0: Only the P-Flash is protected; the D-Flash is unprotected
- Mode 1: Both the P-Flash and D-Flash are protected

The selection of each protection mode and the restrictions imposed are summarized in Table 4.

Table 4 Flash Protection Modes

Flash Protection	Without hardware protection	With hardware protection	
Hardware Protection Mode	-	0	1
Activation	Program a valid password via BSL mode 6		
Selection	Bit 4 of password = 0	Bit 4 of password = 1 MSB of password = 0	Bit 4 of password = 1 MSB of password = 1
P-Flash contents can be read by	Read instructions in any program memory	Read instructions in the P-Flash	Read instructions in the P-Flash or D-Flash
External access to P-Flash	Not possible	Not possible	Not possible

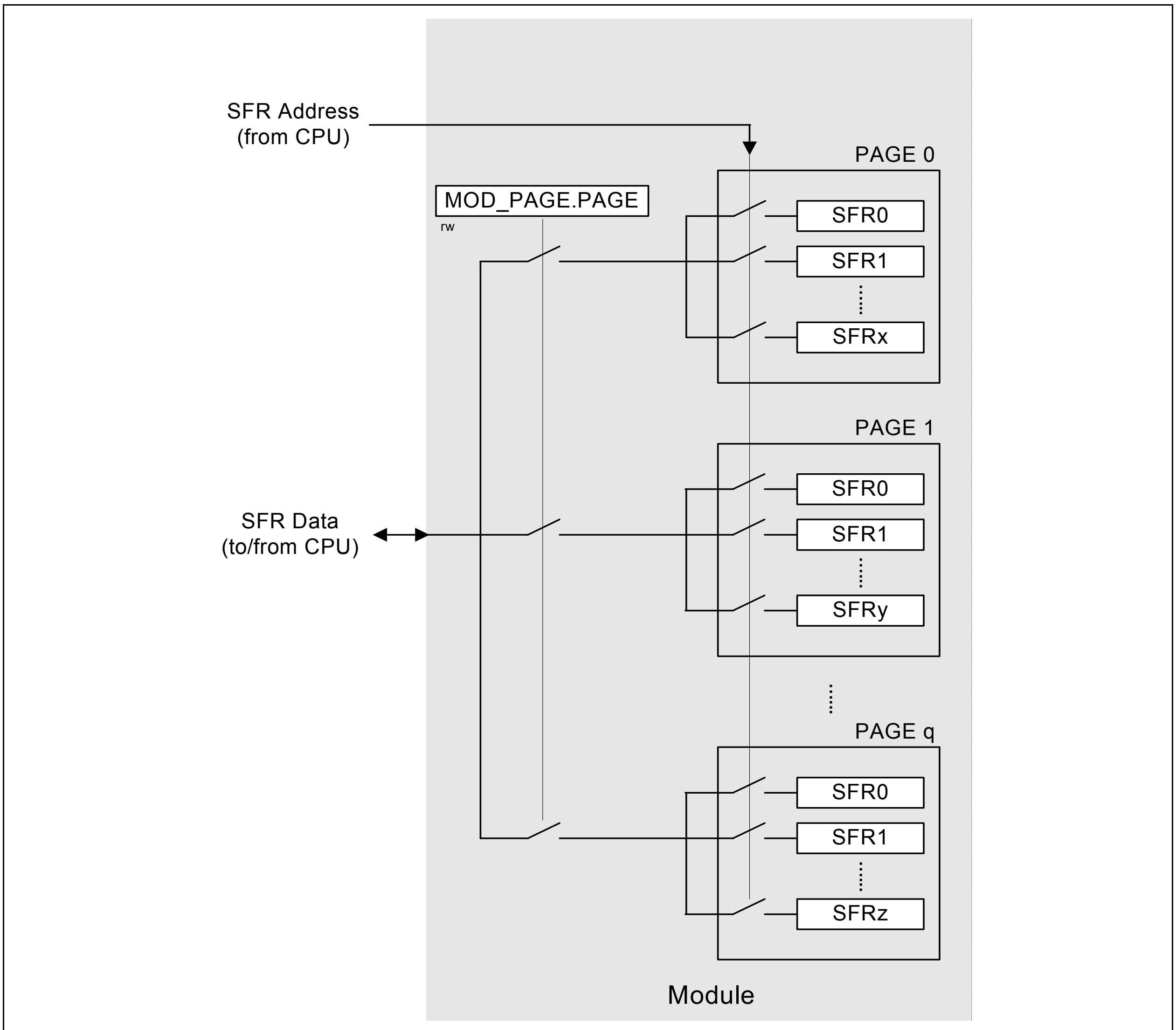

Figure 9 Address Extension by Paging

In order to access a register located in a page different from the actual one, the current page must be exited. This is done by reprogramming the bit field PAGE in the page register. Only then can the desired access be performed.

If an interrupt routine is initiated between the page register access and the module register access, and the interrupt needs to access a register located in another page, the current page setting can be saved, the new one programmed and the old page setting restored. This is possible with the storage fields STx (x = 0 - 3) for the save and restore action of the current page setting. By indicating which storage bit field should be used in parallel with the new page value, a single write operation can:

- Save the contents of PAGE in STx before overwriting with the new value
  (this is done in the beginning of the interrupt routine to save the current page setting and program the new page number); or

3.3 Flash Memory

The Flash memory provides an embedded user-programmable non-volatile memory, allowing fast and reliable storage of user code and data. It is operated from a single 2.5 V supply from the Embedded Voltage Regulator (EVR) and does not require additional programming or erasing voltage. The sectorization of the Flash memory allows each sector to be erased independently.

Features

- In-System Programming (ISP) via UART
- In-Application Programming (IAP)
- Error Correction Code (ECC) for dynamic correction of single-bit errors
- Background program and erase operations for CPU load minimization
- Support for aborting erase operation
- Minimum program width[1] of 32-byte for D-Flash and 64-byte for P-Flash
- 1-sector minimum erase width
- 1-byte read access
- Flash is delivered in erased state (read all zeros)
- Operating supply voltage: 2.5 V ± 7.5 %
- Read access time: 3 × t_{CCLK} = 125 ns[2]
- Program time: 248256 / f_{SYS} = 2.6 ms[3]
- Erase time: 9807360 / f_{SYS} = 102 ms[3]

1) P-Flash: 64-byte wordline can only be programmed once, i.e., one gate disturb allowed.
D-Flash: 32-byte wordline can be programmed twice, i.e., two gate disturbs allowed.

2) Values shown here are typical values. f_{sys} = 96 MHz ± 7.5% (f_{CCLK} = 24 MHz ± 7.5 %) is the maximum frequency range for Flash read access.

3) Values shown here are typical values. f_{sys} = 96 MHz ± 7.5% is the only frequency range for Flash programming and erasing. f_{sysmin} is used for obtaining the worst case timing.

Table 19 shows the Flash data retention and endurance targets.

Table 19 Flash Data Retention and Endurance (Operating Conditions apply)

Retention	Endurance[1)]	Size	Remarks
Program Flash			
20 years	1,000 cycles	up to 32 Kbytes[2)]	for 32-Kbyte Variant
20 years	1,000 cycles	up to 24 Kbytes[2)]	for 24-Kbyte Variant
Data Flash			
20 years	1,000 cycles	4 Kbytes	
5 years	10,000 cycles	1 Kbyte	
2 years	70,000 cycles	512 bytes	
2 years	100,000 cycles	128 bytes	

1) One cycle refers to the programming of all wordlines in a sector and erasing of sector. The Flash endurance data specified in Table 19 is valid only if the following conditions are fulfilled:
- the maximum number of erase cycles per Flash sector must not exceed 100,000 cycles.
- the maximum number of erase cycles per Flash bank must not exceed 300,000 cycles.
- the maximum number of program cycles per Flash bank must not exceed 2,500,000 cycles.

2) If no Flash is used for data, the Program Flash size can be up to the maximum Flash size available in the device variant. Having more Data Flash will mean less Flash is available for Program Flash.

3.3.1 Flash Bank Sectorization

The XC886/888 product family offers Flash devices with either 24 Kbytes or 32 Kbytes of embedded Flash memory. Each Flash device consists of Program Flash (P-Flash) and Data Flash (D-Flash) bank(s) with different sectorization shown in Figure 11. Both types can be used for code and data storage. The label “Data” neither implies that the D-Flash is mapped to the data memory region, nor that it can only be used for data storage. It is used to distinguish the different Flash bank sectorizations.

The 32-Kbyte Flash device consists of 6 P-Flash and 2 D-Flash banks, while the 24-Kbyte Flash device consists of also of 6 P-Flash banks but with the upper 2 banks only 2 Kbytes each, and only 1 D-Flash bank. The XC886/888 ROM devices offer a single 4-Kbyte D-Flash bank.

The P-Flash banks are always grouped in pairs. As such, the P-Flash banks are also sometimes referred to as P-Flash bank pair. Each sector in a P-Flash bank is grouped with the corresponding sector from the other bank within a bank pair to form a P-Flash bank pair sector.

1) BSL mode is automatically entered if no valid password is installed and data at memory address 0000H equals zero.
2) OSC is bypassed in MultiCAN BSL mode
3) Normal user mode with standard JTAG (TCK,TDI,TDO) pins for hot-attach purpose.

Note: The boot options are valid only with the default set of UART and JTAG pins.

3.8 Clock Generation Unit

The Clock Generation Unit (CGU) allows great flexibility in the clock generation for the XC886/888. The power consumption is indirectly proportional to the frequency, whereas the performance of the microcontroller is directly proportional to the frequency. During user program execution, the frequency can be programmed for an optimal ratio between performance and power consumption. Therefore the power consumption can be adapted to the actual application state.

Features

- Phase-Locked Loop (PLL) for multiplying clock source by different factors
- PLL Base Mode
- Prescaler Mode
- PLL Mode
- Power-down mode support

The CGU consists of an oscillator circuit and a PLL. In the XC886/888, the oscillator can be from either of these two sources: the on-chip oscillator (9.6 MHz) or the external oscillator (4 MHz to 12 MHz). The term “oscillator” is used to refer to both on-chip oscillator and external oscillator, unless otherwise stated. After the reset, the on-chip oscillator will be used by default.The external oscillator can be selected via software. In addition, the PLL provides a fail-safe logic to perform oscillator run and loss-of-lock detection. This allows emergency routines to be executed for system recovery or to perform system shut down.

Table 25 shows the VCO range for the XC886/888.

Table 25 VCO Range

f_{VCOmin}	f_{VCOmax}	$f_{VCOFREEmin}$	$f_{VCOFREEmax}$	Unit
150	200	20	80	MHz
100	150	10	80	MHz

3.8.1 Recommended External Oscillator Circuits

The oscillator circuit, a Pierce oscillator, is designed to work with both, an external crystal oscillator or an external stable clock source. It basically consists of an inverting amplifier and a feedback element with XTAL1 as input, and XTAL2 as output.

When using a crystal, a proper external oscillator circuitry must be connected to both pins, XTAL1 and XTAL2. The crystal frequency can be within the range of 4 MHz to 12 MHz. Additionally, it is necessary to have two load capacitances C_{X1} and C_{X2}, and depending on the crystal type, a series resistor R_{X2}, to limit the current. A test resistor R_Q may be temporarily inserted to measure the oscillation allowance (negative resistance) of the oscillator circuitry. R_Q values are typically specified by the crystal vendor. The C_{X1} and C_{X2} values shown in Figure 25 can be used as starting points for the negative resistance evaluation and for non-productive systems. The exact values and related operating range are dependent on the crystal frequency and have to be determined and optimized together with the crystal vendor using the negative resistance method. Oscillation measurement with the final target system is strongly recommended to verify the input amplitude at XTAL1 and to determine the actual oscillation allowance (margin negative resistance) for the oscillator-crystal system.

When using an external clock signal, the signal must be connected to XTAL1. XTAL2 is left open (unconnected).

The oscillator can also be used in combination with a ceramic resonator. The final circuitry must also be verified by the resonator vendor. Figure 25 shows the recommended external oscillator circuitries for both operating modes, external crystal mode and external input clock mode.

3.12 CORDIC Coprocessor

The CORDIC Coprocessor provides CPU with hardware support for the solving of circular (trigonometric), linear (multiply-add, divide-add) and hyperbolic functions.

Features

- Modes of operation
  - Supports all CORDIC operating modes for solving circular (trigonometric), linear (multiply-add, divide-add) and hyperbolic functions
  - Integrated look-up tables (LUTs) for all operating modes
- Circular vectoring mode: Extended support for values of initial X and Y data up to full range of $[-2^{15},(2^{15}-1)]$ for solving angle and magnitude
- Circular rotation mode: Extended support for values of initial Z data up to full range of $[-2^{15},(2^{15}-1)]$, representing angles in the range $[-\pi,((2^{15}-1)/2^{15})\pi]$ for solving trigonometry
- Implementation-dependent operational frequency of up to 80 MHz
- Gated clock input to support disabling of module
- 16-bit accessible data width
  - 24-bit kernel data width plus 2 overflow bits for X and Y each
  - 20-bit kernel data width plus 1 overflow bit for Z
  - With KEEP bit to retain the last value in the kernel register for a new calculation
- 16 iterations per calculation: Approximately 41 clock-cycles or less, from set of start (ST) bit to set of end-of-calculation flag, excluding time taken for write and read access of data bytes.
- Twos complement data processing
  - Only exception: X result data with user selectable option for unsigned result
- X and Y data generally accepted as integer or rational number; X and Y must be of the same data form
- Entries of LUTs are 20-bit signed integers
  - Entries of atan and atanh LUTs are integer representations (S19) of angles with the scaling such that $[-2^{15},(2^{15}-1)]$ represents the range $[-\pi,((2^{15}-1)/2^{15})\pi]$
  - Accessible Z result data for circular and hyperbolic functions is integer in data form of S15
- Emulated LUT for linear function
  - Data form is 1 integer bit and 15-bit fractional part (1.15)
  - Accessible Z result data for linear function is rational number with fixed data form of S4.11 (signed 4Q16)
- Truncation Error
  - The result of a CORDIC calculation may return an approximation due to truncation of LSBs
  - Good accuracy of the CORDIC calculated result data, especially in circular mode
- Interrupt
  - On completion of a calculation

fractional divider) for generating a wide range of baud rates based on its input clock f_{PCLK}, see **Figure 30**.

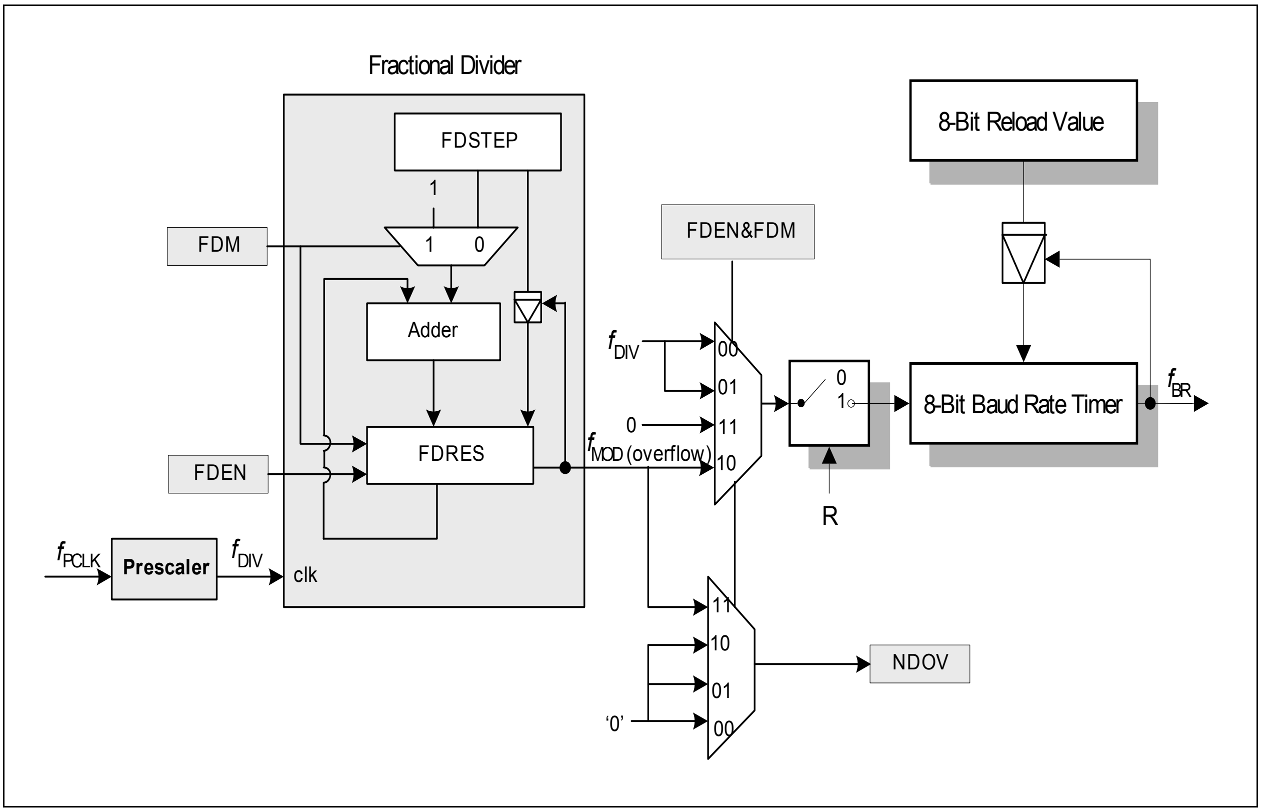

Figure 30 Baud-rate Generator Circuitry

The baud rate timer is a count-down timer and is clocked by either the output of the fractional divider (f_{MOD}) if the fractional divider is enabled (FDCON.FDEN = 1), or the output of the prescaler (f_{DIV}) if the fractional divider is disabled (FDEN = 0). For baud rate generation, the fractional divider must be configured to fractional divider mode (FDCON.FDM = 0). This allows the baud rate control run bit BCON.R to be used to start or stop the baud rate timer. At each timer underflow, the timer is reloaded with the 8-bit reload value in register BG and one clock pulse is generated for the serial channel.

Enabling the fractional divider in normal divider mode (FDEN = 1 and FDM = 1) stops the baud rate timer and nullifies the effect of bit BCON.R. See **Section 3.14**.

The baud rate (f_{BR}) value is dependent on the following parameters:

- Input clock f_{PCLK}
- Prescaling factor (2^{BRPRE}) defined by bit field BRPRE in register BCON
- Fractional divider (STEP/256) defined by register FDSTEP
  (to be considered only if fractional divider is enabled and operating in fractional divider mode)
- 8-bit reload value (BR_VALUE) for the baud rate timer defined by register BG

Table 31 Deviation Error for UART with Fractional Divider enabled

f_{PCLK}	Prescaling Factor (2BRPRE)	Reload Value (BR_VALUE + 1)	STEP	Deviation Error
24 MHz	1	10 (A_H)	197 ($C5_H$)	+0.20 %
12 MHz	1	6 (6_H)	236 (EC_H)	+0.03 %
8 MHz	1	4 (4_H)	236 (EC_H)	+0.03 %
6 MHz	1	3 (3_H)	236 (EC_H)	+0.03 %

3.13.2 Baud Rate Generation using Timer 1

In UART modes 1 and 3 of UART module, Timer 1 can be used for generating the variable baud rates. In theory, this timer could be used in any of its modes. But in practice, it should be set into auto-reload mode (Timer 1 mode 2), with its high byte set to the appropriate value for the required baud rate. The baud rate is determined by the Timer 1 overflow rate and the value of SMOD as follows:

$$\text{Mode 1, 3 baud rate} = \frac{2^{SMOD} \times f_{PCLK}}{32 \times 2 \times (256 - TH1)} \tag{3.7}$$

3.14 Normal Divider Mode (8-bit Auto-reload Timer)

Setting bit FDM in register FDCON to 1 configures the fractional divider to normal divider mode, while at the same time disables baud rate generation (see **Figure 30**). Once the fractional divider is enabled (FDEN = 1), it functions as an 8-bit auto-reload timer (with no relation to baud rate generation) and counts up from the reload value with each input clock pulse. Bit field RESULT in register FDRES represents the timer value, while bit field STEP in register FDSTEP defines the reload value. At each timer overflow, an overflow flag (FDCON.NDOV) will be set and an interrupt request generated. This gives an output clock f_{MOD} that is 1/n of the input clock f_{DIV}, where n is defined by 256 - STEP.

The output frequency in normal divider mode is derived as follows:

$$f_{MOD} = f_{DIV} \times \frac{1}{256 - STEP} \tag{3.8}$$

3.15 LIN Protocol

The UART module can be used to support the Local Interconnect Network (LIN) protocol for both master and slave operations. The LIN baud rate detection feature, which consists of the hardware logic for Break and Synch Byte detection, provides the capability to detect the baud rate within LIN protocol using Timer 2. This allows the UART to be synchronized to the LIN baud rate for data transmission and reception.

Note: The LIN baud rate detection feature is available for use only with UART. To use UART1 for LIN communication, software has to be implemented to detect the Break and Synch Byte.

LIN is a holistic communication concept for local interconnected networks in vehicles. The communication is based on the SCI (UART) data format, a single-master/multiple-slave concept, a clock synchronization for nodes without stabilized time base. An attractive feature of LIN is self-synchronization of the slave nodes without a crystal or ceramic resonator, which significantly reduces the cost of hardware platform. Hence, the baud rate must be calculated and returned with every message frame.

The structure of a LIN frame is shown in **Figure 31**. The frame consists of the:

- Header, which comprises a Break (13-bit time low), Synch Byte (55_H), and ID field
- Response time
- Data bytes (according to UART protocol)
- Checksum

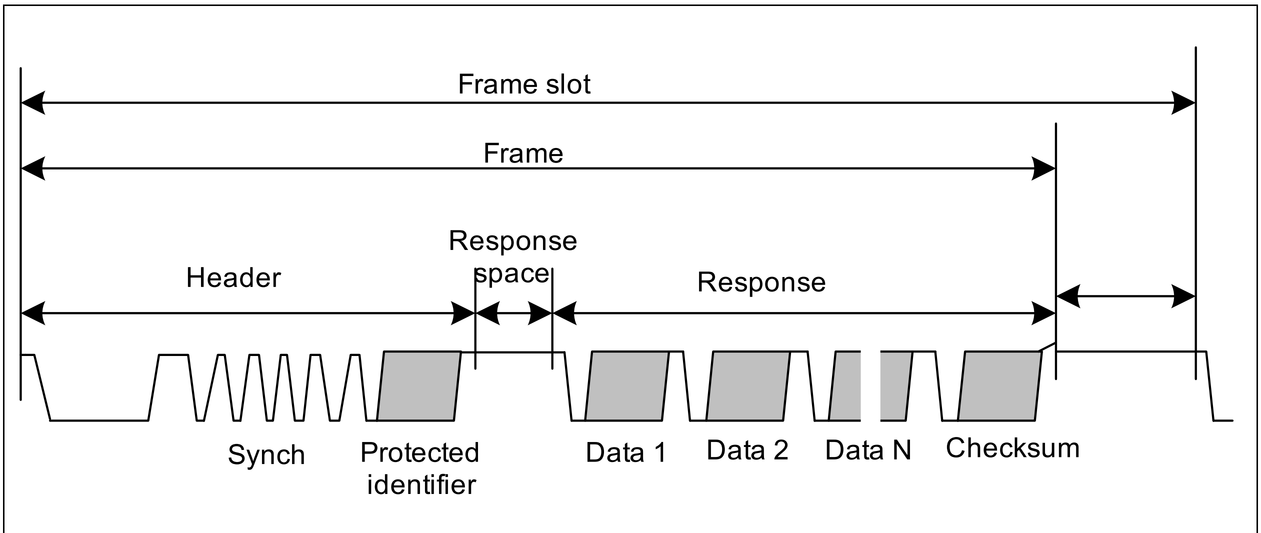

Figure 31 Structure of LIN Frame

3.15.1 LIN Header Transmission

LIN header transmission is only applicable in master mode. In the LIN communication, a master task decides when and which frame is to be transferred on the bus. It also identifies a slave task to provide the data transported by each frame. The information needed for the handshaking between the master and slave tasks is provided by the master task through the header portion of the frame.

The header consists of a break and synch pattern followed by an identifier. Among these three fields, only the break pattern cannot be transmitted as a normal 8-bit UART data. The break must contain a dominant value of 13 bits or more to ensure proper synchronization of slave nodes.

In the LIN communication, a slave task is required to be synchronized at the beginning of the protected identifier field of frame. For this purpose, every frame starts with a sequence consisting of a break field followed by a synch byte field. This sequence is unique and provides enough information for any slave task to detect the beginning of a new frame and be synchronized at the start of the identifier field.

Upon entering LIN communication, a connection is established and the transfer speed (baud rate) of the serial communication partner (host) is automatically synchronized in the following steps:

STEP 1: Initialize interface for reception and timer for baud rate measurement

STEP 2: Wait for an incoming LIN frame from host

STEP 3: Synchronize the baud rate to the host

STEP 4: Enter for Master Request Frame or for Slave Response Frame

Note: Re-synchronization and setup of baud rate are always done for ***every*** *Master Request Header or Slave Response Header LIN frame.*

3.18 Timer 2 and Timer 21

Timer 2 and Timer 21 are 16-bit general purpose timers (THL2) that are fully compatible and have two modes of operation, a 16-bit auto-reload mode and a 16-bit one channel capture mode, see **Table 33**. As a timer, the timers count with an input clock of PCLK/12 (if prescaler is disabled). As a counter, they count 1-to-0 transitions on pin T2. In the counter mode, the maximum resolution for the count is PCLK/24 (if prescaler is disabled).

Table 33 Timer 2 Modes

Mode	Description
Auto-reload	**Up/Down Count Disabled** • Count up only • Start counting from 16-bit reload value, overflow at $FFFF_H$ • Reload event configurable for trigger by overflow condition only, or by negative/positive edge at input pin T2EX as well • Programmble reload value in register RC2 • Interrupt is generated with reload event
	Up/Down Count Enabled • Count up or down, direction determined by level at input pin T2EX • No interrupt is generated • Count up – Start counting from 16-bit reload value, overflow at $FFFF_H$ – Reload event triggered by overflow condition – Programmble reload value in register RC2 • Count down – Start counting from $FFFF_H$, underflow at value defined in register RC2 – Reload event triggered by underflow condition – Reload value fixed at $FFFF_H$
Channel capture	• Count up only • Start counting from 0000_H, overflow at $FFFF_H$ • Reload event triggered by overflow condition • Reload value fixed at 0000_H • Capture event triggered by falling/rising edge at pin T2EX • Captured timer value stored in register RC2 • Interrupt is generated with reload or capture event

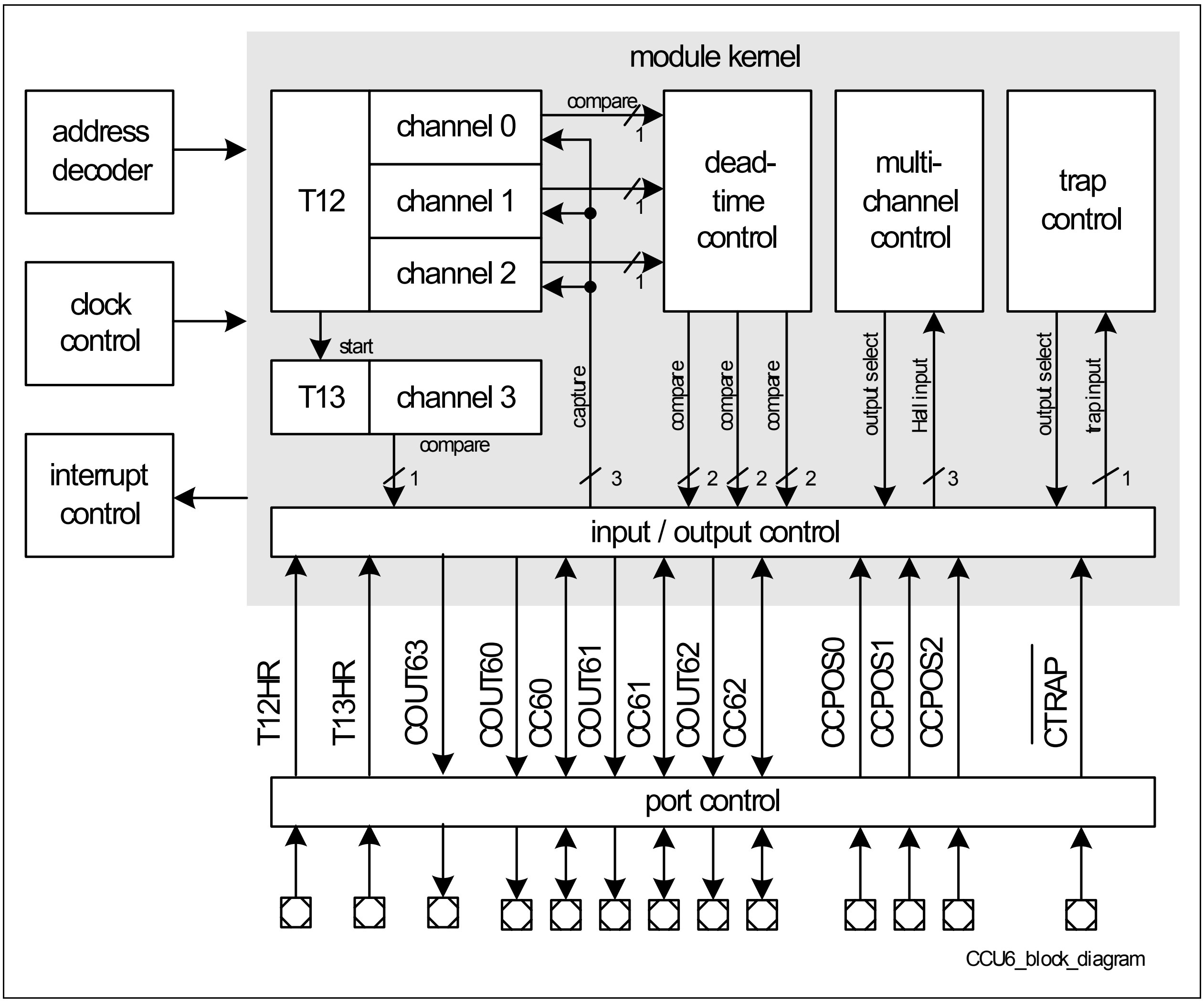

Figure 33 CCU6 Block Diagram

- CAN functionality according to CAN specification V2.0 B active.
- Dedicated control registers are provided for each CAN node.
- A data transfer rate up to 1 MBaud is supported.
- Flexible and powerful message transfer control and error handling capabilities are implemented.
- Advanced CAN bus bit timing analysis and baud rate detection can be performed for each CAN node via the frame counter.
- Full-CAN functionality: A set of 32 message objects can be individually
  - allocated (assigned) to any CAN node
  - configured as transmit or receive object
  - setup to handle frames with 11-bit or 29-bit identifier
  - counted or assigned a timestamp via a frame counter
  - configured to remote monitoring mode
- Advanced Acceptance Filtering:
  - Each message object provides an individual acceptance mask to filter incoming frames.
  - A message object can be configured to accept only standard or only extended frames or to accept both standard and extended frames.
  - Message objects can be grouped into 4 priority classes.
  - The selection of the message to be transmitted first can be performed on the basis of frame identifier, IDE bit and RTR bit according to CAN arbitration rules.
- Advanced Message Object Functionality:
  - Message Objects can be combined to build FIFO message buffers of arbitrary size, which is only limited by the total number of message objects.
  - Message objects can be linked to form a gateway to automatically transfer frames between 2 different CAN buses. A single gateway can link any two CAN nodes. An arbitrary number of gateways may be defined.
- Advanced Data Management:
  - The Message objects are organized in double chained lists.
  - List reorganizations may be performed any time, even during full operation of the CAN nodes.
  - A powerful, command driven list controller manages the organization of the list structure and ensures consistency of the list.
  - Message FIFOs are based on the list structure and can easily be scaled in size during CAN operation.
  - Static Allocation Commands offer compatibility with TwinCAN applications, which are not list based.
- Advanced Interrupt Handling:
  - Up to 8 interrupt output lines are available. Most interrupt requests can be individually routed to one of the 8 interrupt output lines.
  - Message postprocessing notifications can be flexibly aggregated into a dedicated register field of 64 notification bits.

Table 40 ADC Characteristics (Operating Conditions apply; V_{DDP} = 5V Range)

Parameter	Symbol		Limit Values			Unit	Test Conditions/ Remarks
			min.	typ .	max.		
Overload current coupling factor for digital I/O pins	K_{OVD}	CC	–	–	5.0 x 10^{-3}	–	$I_{OV} > 0$ [1)3)]
			–	–	1.0 x 10^{-2}	–	$I_{OV} < 0$ [1)3)]
Switched capacitance at the reference voltage input	C_{AREFSW}	CC	–	10	20	pF	[1)4)]
Switched capacitance at the analog voltage inputs	C_{AINSW}	CC	–	5	7	pF	[1)5)]
Input resistance of the reference input	R_{AREF}	CC	–	1	2	kΩ	[1)]
Input resistance of the selected analog channel	R_{AIN}	CC	–	1	1.5	kΩ	[1)]

1) Not subjected to production test, verified by design/characterization
2) TUE is tested at V_{AREF} = 5.0 V, V_{AGND} = 0 V, V_{DDP} = 5.0 V.
3) An overload current (I_{OV}) through a pin injects a certain error current (I_{INJ}) into the adjacent pins. This error current adds to the respective pin's leakage current (I_{OZ}). The amount of error current depends on the overload current and is defined by the overload coupling factor K_{OV}. The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it. The total current through a pin is $|I_{TOT}| = |I_{OZ1}| + (|I_{OV}| \times K_{OV})$. The additional error current may distort the input voltage on analog inputs.
4) This represents an equivalent switched capacitance. This capacitance is not switched to the reference voltage at once. Instead of this, smaller capacitances are successively switched to the reference voltage.
5) The sampling capacity of the conversion C-Network is pre-charged to $V_{AREF}/2$ before connecting the input to the C-Network. Because of the parasitic elements, the voltage measured at ANx is lower than $V_{AREF}/2$.

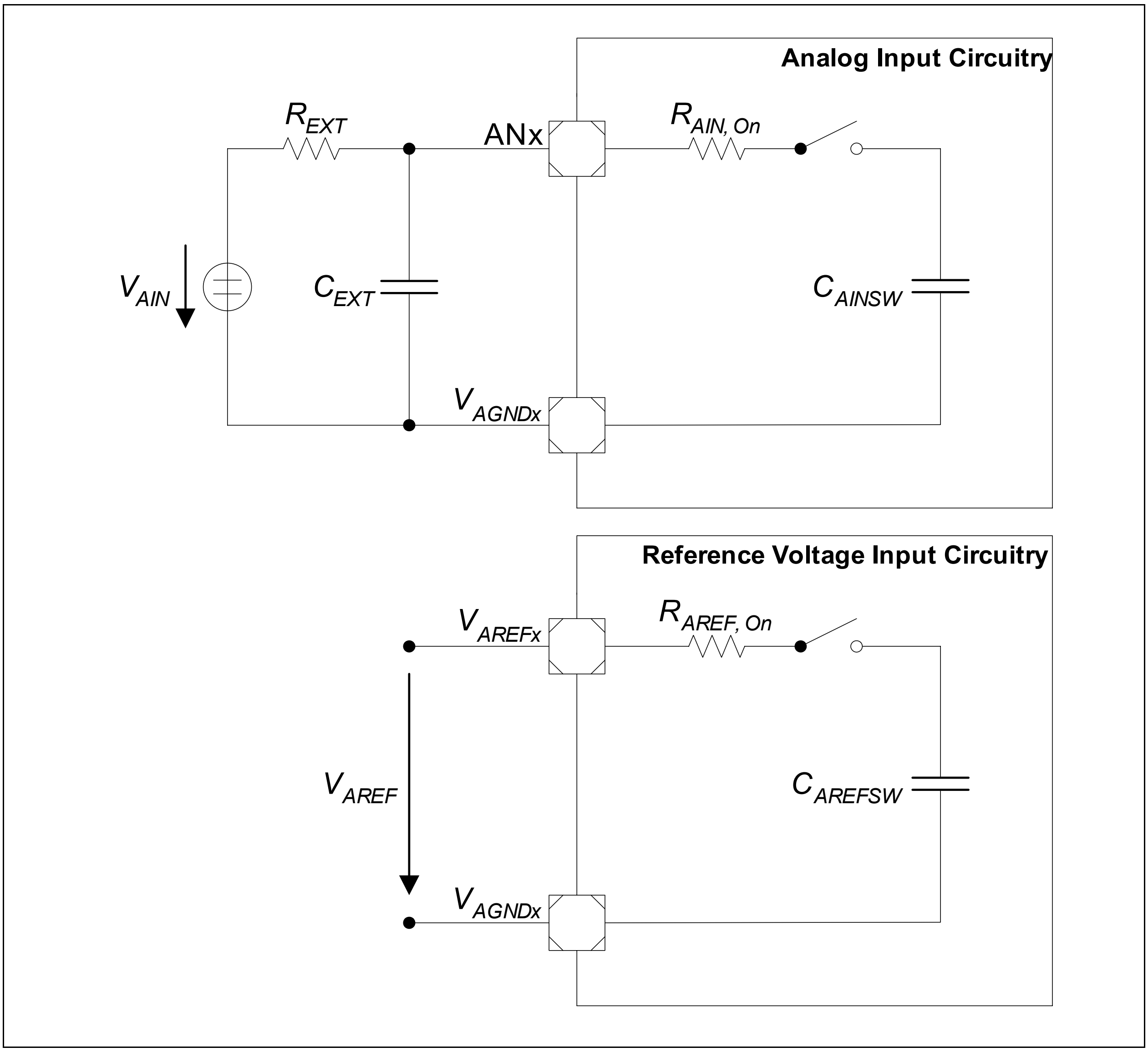

Figure 39 ADC Input Circuits

Table 42 Power Down Current (Operating Conditions apply; V_{DDP} = 5V range)

Parameter	Symbol	Limit Values		Unit	Test Condition
		typ.[1]	max.[2]		
V_{DDP} = 5V Range					
Power-Down Mode	I_{PDP}	1	10	μA	T_A = + 25 °C[3)4)]
		-	30	μA	T_A = + 85 °C[4)5)]

1) The typical I_{PDP} values are measured at V_{DDP} = 5.0 V.
2) The maximum I_{PDP} values are measured at V_{DDP} = 5.5 V.
3) I_{PDP} has a maximum value of 200 μA at T_A = + 125 °C.
4) I_{PDP} is measured with: $\overline{\text{RESET}}$ = V_{DDP}, V_{AGND}= V_{SS}, RXD/INT0 = V_{DDP}; rest of the ports are programmed to be input with either internal pull devices enabled or driven externally to ensure no floating inputs.
5) Not subjected to production test, verified by design/characterization.

5.3 Quality Declaration

Table 2 shows the characteristics of the quality parameters in the XC886/888.

Table 2 Quality Parameters

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	V_{HBM}	-	2000	V	Conforming to EIA/JESD22-A114-B[1)]
ESD susceptibility according to Charged Device Model (CDM) pins	V_{CDM}	-	500	V	Conforming to JESD22-C101-C[1)]

1) Not all parameters are 100% tested, but are verified by design/characterization and test correlation.

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